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AMENDMENTS TO THE SPECIFICATION

Please replace the paragraph at page 3, lines 16-28, with the following amended paragraph.

Q' Fig. 1 is a schematic block diagram of a system 100 for monitoring a semiconductor processing system 102 in accordance with the present invention. The system 100 includes an image collector 110, such as a very small analog or digital camera, associated with an enclosed chamber 120 of the processing system 102. In particular, part of the image collector 110 is located within the interior of the chamber 120 for collecting images of the contents and operation within the chamber. The image collector 110 provides a signal indicative of a visual representation of the interior of the chamber 120 to a viewing station 130 via a communications link 140. The viewing station ~~140~~ 130 includes a display 150 (e.g., a PC monitor or TV screen) at which a technician may visually inspect the interior of the chamber 120 according to the collected images.